



MIL-PRF-38534

HYBRID MICROCIRCUIT CERTIFICATION

**FOR
CLASS H
IS HEREBY AWARDED TO**

CMC Electronics Inc.

600 Dr. Frederik Phillips Boulevard

Ville Saint-Laurent, Quebec

Canada H4M 2S9

THIS CERTIFICATION IS VALID UNTIL TERMINATED BY WRITTEN NOTIFICATION FROM DLA LAND AND MARITIME. REFERENCE DLA LAND AND MARITIME LETTER VQ(VQH-13-026350) FOR DETAILS PERTAINING TO THIS CERTIFICATION.

SAMUEL E. MERRITT
Director, Operations Support Directorate
DLA Land and Maritime



DEFENSE LOGISTICS AGENCY
LAND AND MARITIME
POST OFFICE BOX 3990
COLUMBUS, OH 43218-3990

May 14, 2013

Mr. Jean-Marc Perreault
CMC Electronics Inc.
600 Dr. Frederik Philips Boulevard
Ville Saint-Laurent, Quebec
Canada H4M 2S9

Dear Mr. Perreault:

Re: Class H MIL-PRF-38534 Certification, Hybrid Microcircuits, FSC 5962, VQ(VQH-13-026350), CN# 039441

Your hybrid facility at the above address was sample audited the week of May 7, 2012 for compliance with MIL-PRF-38534 Class H. An acceptable level of confidence has been established that compliance with these requirements exists. Therefore, CMC Electronics, Incorporated's Class H certification is continued effective May 13, 2013.

This certification is for the following:

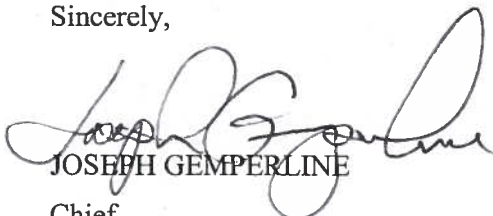
- a. Quality Management Plan: 411-178205-000 Rev. T
- b. Conversion of Customer Requirements: 411-128210-000 Rev. U
- c. Controlled documentation baseline for processing MIL-PRF-38534 devices: 411-178206-000 Rev. AE

This certification is valid until terminated by written notification from the qualifying activity. The normal period of certification is two years from the date of the audit and, if warranted, may be withdrawn by DLA Land and Maritime at any time. Your facility may be re-audited on a drop-in basis at any time.

All screening, qualification, conformance, and periodic inspection must be performed at a facility which has a DLA Land and Maritime letter of Laboratory Suitability for the applicable test method and condition. QML manufacturers shall notify the qualifying activity immediately after learning of a GIDEP alert, problem advisory or major quality/reliability problem affecting QML products. This includes failure to perform screening or sample testing (including inspection) in accordance with MIL-PRF-38534. Failure to provide notification may be grounds for removal from QML-38534.

If you have any questions, please contact Mr. Hancock at (614) 692-1309.

Sincerely,



JOSEPH GEMPERLINE

Chief
Sourcing and Qualifications Division

Enclosure



DEFENSE LOGISTICS AGENCY

LAND AND MARITIME
POST OFFICE BOX 3990
COLUMBUS, OH 43218-3990

May 14, 2013

Mr. Jean-Marc Perreault
CMC Electronics Inc.
600 Dr. Frederik Philips Boulevard
Ville Saint-Laurent, Quebec
Canada H4M 2S9

Dear Mr. Perreault:

Re: Laboratory Suitability Status, Hybrid Microcircuits, MIL-PRF-38534, FSC 5962, VQH-13-026351, CN# 039441

Based on a sample audit and review of your test methods the week of May 7, 2012, a satisfactory confidence level of Laboratory Suitability has been demonstrated. Therefore, your facility at 600 Dr. Frederik Philips Boulevard in Quebec Canada is considered suitably equipped to perform testing on military devices for the following test methods of MIL-STD-883:

| <u>TEST</u> | <u>METHOD</u> | <u>CONDITION</u> |
|--------------------------------|---------------|----------------------------------|
| Insulation Resistance | 1003 | 600Vdc, 100nA |
| Moisture Resistance | 1004 | N/A |
| Life Test | 1005 | B, 125°C, T _a , Air |
| Stabilization Bake | 1008 | C (150°C), F |
| Temperature Cycling | 1010 | C |
| Thermal Shock | 1011 | C |
| Seal | 1014 | A ₁ , C ₁ |
| Burn-In | 1015 | B, 125°C, T _a , Air |
| Constant Acceleration | 2001 | A-E, 3000g (Y ₁ Axis) |
| Mechanical Shock | 2002 | B |
| Solderability | 2003 | N/A |
| Lead Integrity | 2004 | B ₂ |
| External Visual | 2009 | N/A |
| Internal Visual (Monolithic) | 2010 | B |
| Bond Strength | 2011 | D |
| Internal Visual Mechanical | 2014 | N/A |
| Resistance to Solvents | 2015 | N/A |
| Physical Dimensions | 2016 | N/A |
| Internal Visual (Hybrid) | 2017 | H |
| Die Shear | 2019 | N/A |
| PIND | 2020 | B |
| Non-Destruct Bond Pull | 2023 | N/A |
| Internal Visual (Passive) | 2032 | H |
| *Internal Visual (Transistors) | 2072 | N/A |
| *Internal Visual (Diodes) | 2073 | N/A |

*Test Methods in MIL-STD-750

All screening, conformance inspection, periodic inspection, and qualification tests must be performed by a facility that has been issued Laboratory Suitability by DLA Land and Maritime-VQ for the applicable test method and condition.

This Laboratory Suitability is valid until withdrawn by this Center. This Laboratory Suitability is subject to the conditions stated in DoD 4120.24-M and SD-6.

If you have any questions, please contact Mr. Hancock at (614) 692-1309.

Sincerely,



JAMES ESCHMEYER
Chief
Hybrid Devices Branch

